

Notice of References Cited	Application/Control No. 10/614,642	Applicant(s)/Patent Under Reexamination DIXIT ET AL.	
	Examiner Cynthia Britt	Art Unit 2138	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,835,429	11-1998	Schwarz, William	365/201
*	B	US-6,272,588	08-2001	Johnston et al.	711/106
*	C	US-6,496,947	12-2002	Schwarz, William D.	714/30
*	D	US-6,681,350	01-2004	Adams et al.	714/718
*	E	US-6,697,978	02-2004	Bear et al.	714/718
*	F	US-5,577,050	11-1996	Bair et al.	714/710
*	G	US-6,255,836	07-2001	Schwarz et al.	324/763
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"An Efficient BIST Method for Testing of Embedded SRAMs" by Tehranipour et al. International Symposium on Circuits and Systems, 2001 Publication Date: 2001 Volume 5, pages 73-76 ISBN: 0-7803-6685-9 INSPEC Accession Number: 7042567
	V	"Quick Address Detection of Anomalous Memory Cells in a Flash Memory Test Structure" by Himeno, et al. IEEE Transactions on Semiconductor Manufacturing, Publication Date: May 1997 Volume: 10, Issue: 2 pages: 196-200 INSPEC Accession Number: 5570257
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.